Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/611,896	LEE ET AL.
Examiner	Art Unit
Thien F. Tran	2811

SEARCHED					
Class	Subclass	Date	Examiner		
257	52, 57, 59-61, 72	6/8/2006	TΤ		
			<u> </u>		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
-					

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Interference search history printout	6/8/2006	тт
,		
		:
•		